Special Issue

Test and Monitoring of Aging Effects in Electronics

Message from the Guest Editors

The purpose of this Special Issue is to let academic and industrial researchers propose innovative solutions for enhancing state-of-the-art in the domains of testing and aging monitoring. The potential topics of the Special Issue include but are not limited to:

- Analog and digital modules to support aging monitoring and fault diagnosis;
- Burn-in enhancements;
- Machine learning and Artificial Intelligence techniques for aging characterization and early failure detection;
- Design, validation, and test of monitoring and DfT infrastructure;
- Hardware/software or hybrid solutions for in-field test and diagnosis of safety-critical systems;
- Aging-oriented fault modeling, and test generation;
- Industrial and academic case studies.

Guest Editors

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Deadline for manuscript submissions

closed (28 February 2022)

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About the Journal

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Editor-in-Chief

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